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## **Microbeam analysis — Scanning electron microscopy — Guidelines for calibrating image magnification**

*Analyse par microfaisceaux — Microscopie électronique à balayage  
— Lignes directrices pour l'étalonnage du grandissement d'image*



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ISO copyright office  
Ch. de Blandonnet 8 • CP 401  
CH-1214 Vernier, Geneva, Switzerland  
Tel. +41 22 749 01 11  
Fax +41 22 749 09 47  
[copyright@iso.org](mailto:copyright@iso.org)  
[www.iso.org](http://www.iso.org)

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## Foreword

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The committee responsible for this document is ISO/TC 202, *Microbeam analysis*, Subcommittee SC 4, *Scanning electron microscopy (SEM)*.

This second edition cancels and replaces the first edition (ISO 16700:2004), which has been technically revised.

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## Introduction

The scanning electron microscope is widely used to investigate the surface structure of a range of important materials such as semiconductors, metals, polymers, glass, food and biological materials, and this International Standard is relevant to the need for magnification calibration of the images. It describes the requirements for calibration of the image magnification in the scanning electron microscope using a reference material or a certified reference material.